

Appl. No. 09/896,426
Amdt. dated 02/07/2005
Reply to Office action of 10/05/2004

Amendments to the Specification

Please add the following new paragraph on page 7, immediately before the final paragraph of the specification:

In place of the all-software approach described above it is also possible to improve pixel arrays as follows: After testing the pixel array to determine where bad pixels are located, these bad pixels are disconnected from the array and then connected to one or more of their nearest neighbors so that these nearest neighbors, in combination, will serve as replacements for the bad pixels. The steps of disconnecting and then re-connecting bad pixels can be accomplished through use of fusible link or anti-fuse technology. Note that testing of the pixel array (to determine at which address a bad pixel is located) is performed prior to dicing into chips. This enables the steps of disconnecting and then reconnecting the bad pixels to be accomplished by means of chip-level wiring.